

AMD Xilinx - XC5202-5PQ100C Datasheet



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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	64
Number of Logic Elements/Cells	256
Total RAM Bits	-
Number of I/O	81
Number of Gates	3000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc5202-5pq100c

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XC5200 Series Field Programmable Gate Arrays

XC3000 family: XC5200 devices support an additional programming mode: Peripheral Synchronous.

XC3000 family: The XC5200 family does not support Power-down, but offers a Global 3-state input that does not reset any flip-flops.

XC3000 family: The XC5200 family does not provide an on-chip crystal oscillator amplifier, but it does provide an internal oscillator from which a variety of frequencies up to 12 MHz are available.

Architectural Overview

Figure 1 presents a simplified, conceptual overview of the XC5200 architecture. Similar to conventional FPGAs, the XC5200 family consists of programmable IOBs, programmable logic blocks, and programmable interconnect. Unlike other FPGAs, however, the logic and local routing resources of the XC5200 family are combined in flexible VersaBlocks (Figure 2). General-purpose routing connects to the VersaBlock through the General Routing Matrix (GRM).

VersaBlock: Abundant Local Routing Plus Versatile Logic

The basic logic element in each VersaBlock structure is the Logic Cell, shown in Figure 3. Each LC contains a 4-input function generator (F), a storage device (FD), and control logic. There are five independent inputs and three outputs to each LC. The independence of the inputs and outputs allows the software to maximize the resource utilization within each LC. Each Logic Cell also contains a direct feedthrough path that does not sacrifice the use of either the function generator or the register; this feature is a first for FPGAs. The storage device is configurable as either a D flip-flop or a latch. The control logic consists of carry logic for fast implementation of arithmetic functions, which can also be configured as a cascade chain allowing decode of very wide input functions.



Figure 1: XC5200 Architectural Overview



Figure 2: VersaBlock



Figure 3: XC5200 Logic Cell (Four LCs per CLB)

can also be independently disabled for any flip-flop. CLR is active High. It is not invertible within the CLB.



Figure 8: Schematic Symbols for Global Reset

Global Reset

A separate Global Reset line clears each storage element during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GR) does not compete with other routing resources; it uses a dedicated distribution network.

GR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GR pin of the STARTUP symbol. (See Figure 9.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global Reset signal. Alternatively, GR can be driven from any internal node.

Using FPGA Flip-Flops and Latches

The abundance of flip-flops in the XC5200 Series invites pipelined designs. This is a powerful way of increasing performance by breaking the function into smaller subfunctions and executing them in parallel, passing on the results through pipeline flip-flops. This method should be seriously considered wherever throughput is more important than latency.

To include a CLB flip-flop, place the appropriate library symbol. For example, FDCE is a D-type flip-flop with clock enable and asynchronous clear. The corresponding latch symbol is called LDCE.

In XC5200-Series devices, the flip-flops can be used as registers or shift registers without blocking the function generators from performing a different, perhaps unrelated task. This ability increases the functional capacity of the devices.

The CLB setup time is specified between the function generator inputs and the clock input CK. Therefore, the specified CLB flip-flop setup time includes the delay through the function generator.

Three-State Buffers

The XC5200 family has four dedicated Three-State Buffers (TBUFs, or BUFTs in the schematic library) per CLB (see Figure 9). The four buffers are individually configurable through four configuration bits to operate as simple non-inverting buffers or in 3-state mode. When in 3-state mode the CLB output enable (TS) control signal drives the enable to all four buffers. Each TBUF can drive up to two horizontal and/or two vertical Longlines. These 3-state buffers can be used to implement multiplexed or bidirectional buses on the horizontal or vertical longlines, saving logic resources.

The 3-state buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 4.

Table 4: Three-State Buffer Functionality

IN	Т	OUT
Х	1	Z
IN	0	IN

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array.

The longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver. To ensure the longline goes high when no buffers are on, add an additional BUFT to drive the output High during all of the previously undefined states.

Figure 10 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.



Figure 9: XC5200 3-State Buffers

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Figure 10: 3-State Buffers Implement a Multiplexer

Input/Output Blocks

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals.

The I/O block, shown in Figure 11, consists of an input buffer and an output buffer. The output driver is an 8-mA full-rail CMOS buffer with 3-state control. Two slew-rate control modes are supported to minimize bus transients. Both the output buffer and the 3-state control are invertible. The input buffer has globally selected CMOS or TTL input thresholds. The input buffer is invertible and also provides a programmable delay line to assure reliable chip-to-chip set-up and hold times. Minimum ESD protection is 3 KV using the Human Body Model.



Figure 11: XC5200 I/O Block

IOB Input Signals

The XC5200 inputs can be globally configured for either TTL (1.2V) or CMOS thresholds, using an option in the bitstream generation software. There is a slight hysteresis of about 300mV.

The inputs of XC5200-Series 5-Volt devices can be driven by the outputs of any 3.3-Volt device, if the 5-Volt inputs are in TTL mode.

Supported sources for XC5200-Series device inputs are shown in Table 5.

Table 5: Supported Sources	for XC5200-Series	Device
Inputs		

	XC5200 Input Mode			
Source	5 V, TTL	5 V, CMOS		
Any device, Vcc = 3.3 V, CMOS outputs	\checkmark	Unreliable		
Any device, Vcc = 5 V, TTL outputs	\checkmark	Data		
Any device, Vcc = 5 V, CMOS outputs	\checkmark	\checkmark		

Optional Delay Guarantees Zero Hold Time

XC5200 devices do not have storage elements in the IOBs. However, XC5200 IOBs can be efficiently routed to CLB flip-flops or latches to store the I/O signals.

The data input to the register can optionally be delayed by several nanoseconds. With the delay enabled, the setup time of the input flip-flop is increased so that normal clock routing does not result in a positive hold-time requirement. A positive hold time requirement can lead to unreliable, temperature- or processing-dependent operation.

The input flip-flop setup time is defined between the data measured at the device I/O pin and the clock input at the CLB (not at the clock pin). Any routing delay from the device clock pin to the clock input of the CLB must, therefore, be subtracted from this setup time to arrive at the real setup time requirement relative to the device pins. A short specified setup time might, therefore, result in a negative setup time at the device pins, i.e., a positive hold-time requirement.

When a delay is inserted on the data line, more clock delay can be tolerated without causing a positive hold-time requirement. Sufficient delay eliminates the possibility of a data hold-time requirement at the external pin. The maximum delay is therefore inserted as the software default.

The XC5200 IOB has a one-tap delay element: either the delay is inserted (default), or it is not. The delay guarantees a zero hold time with respect to clocks routed through any of the XC5200 global clock buffers. (See "Global Lines" on page 96 for a description of the global clock buffers in the XC5200.) For a shorter input register setup time, with

segments span the width and height of the chip, respectively.

Two low-skew horizontal and vertical unidirectional global-line segments span each row and column of the chip, respectively.

Single- and Double-Length Lines

The single- and double-length bidirectional line segments make up the bulk of the routing channels. The double-length lines hop across every other CLB to reduce the propagation delays in speed-critical nets. Regenerating the signal strength is recommended after traversing three or four such segments. Xilinx place-and-route software automatically connects buffers in the path of the signal as necessary. Single- and double-length lines cannot drive onto Longlines and global lines; Longlines and global lines can, however, drive onto single- and double-length lines. As a general rule, Longline and global-line connections to the general routing matrix are unidirectional, with the signal direction from these lines toward the routing matrix.

Longlines

Longlines are used for high-fan-out signals, 3-state busses, low-skew nets, and faraway destinations. Row and column splitter PIPs in the middle of the array effectively double the total number of Longlines by electrically dividing them into two separated half-lines. Longlines are driven by the 3-state buffers in each CLB, and are driven by similar buffers at the periphery of the array from the VersaRing I/O Interface.

Bus-oriented designs are easily implemented by using Longlines in conjunction with the 3-state buffers in the CLB and in the VersaRing. Additionally, weak keeper cells at the periphery retain the last valid logic level on the Longlines when all buffers are in 3-state mode.

Longlines connect to the single-length or double-length lines, or to the logic inside the CLB, through the General Routing Matrix. The only manner in which a Longline can be driven is through the four 3-state buffers; therefore, a Longline-to-Longline or single-line-to-Longline connection through PIPs in the General Routing Matrix is not possible. Again, as a general rule, long- and global-line connections to the General Routing Matrix are unidirectional, with the signal direction from these lines toward the routing matrix.

The XC5200 family has no pull-ups on the ends of the Longlines sourced by TBUFs, unlike the XC4000 Series. Consequently, wired functions (i.e., WAND and WORAND) and wide multiplexing functions requiring pull-ups for undefined states (i.e., bus applications) must be implemented in a different way. In the case of the wired functions, the same functionality can be achieved by taking advantage of the carry/cascade logic described above, implementing a wide logic function in place of the wired function. In the case of 3-state bus applications, the user must insure that all states of the multiplexing function are defined. This process is as simple as adding an additional TBUF to drive the bus High when the previously undefined states are activated.

Global Lines

Global buffers in Xilinx FPGAs are special buffers that drive a dedicated routing network called Global Lines, as shown in Figure 16. This network is intended for high-fanout clocks or other control signals, to maximize speed and minimize skewing while distributing the signal to many loads.

The XC5200 family has a total of four global buffers (BUFG symbol in the library), each with its own dedicated routing channel. Two are distributed vertically and two horizontally throughout the FPGA.

The global lines provide direct input only to the CLB clock pins. The global lines also connect to the General Routing Matrix to provide access from these lines to the function generators and other control signals.

Four clock input pads at the corners of the chip, as shown in Figure 16, provide a high-speed, low-skew clock network to each of the four global-line buffers. In addition to the dedicated pad, the global lines can be sourced by internal logic. PIPs from several routing channels within the VersaRing can also be configured to drive the global-line buffers.

Details of all the programmable interconnect for a CLB is shown in Figure 17.



Figure 16: Global Lines

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Figure 17: Detail of Programmable Interconnect Associated with XC5200 Series CLB

VersaRing Input/Output Interface

The VersaRing, shown in Figure 18, is positioned between the core logic and the pad ring; it has all the routing resources of a VersaBlock without the CLB logic. The VersaRing decouples the core logic from the I/O pads. Each VersaRing Cell provides up to four pad-cell connections on one side, and connects directly to the CLB ports on the other side.



Figure 18: VersaRing I/O Interface

Boundary Scan

The "bed of nails" has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE boundary scan standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can imbed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan-compatible IC. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two. XC5200 devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, SAMPLE/PRELOAD, and BYPASS instructions. The TAP can also support two USERCODE instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output.

Boundary-scan operation is independent of individual IOB configuration and package type. All IOBs are treated as independently controlled bidirectional pins, including any unbonded IOBs. Retaining the bidirectional test capability after configuration provides flexibility for interconnect testing.

Also, internal signals can be captured during EXTEST by connecting them to unbonded IOBs, or to the unused outputs in IOBs used as unidirectional input pins. This technique partially compensates for the lack of INTEST support.

The user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in Xilinx devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note XAPP 017: *"Boundary Scan in XC4000 and XC5200 Series devices"*

Figure 19 on page 99 is a diagram of the XC5200-Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

The public boundary-scan instructions are always available prior to configuration. After configuration, the public instructions and any USERCODE instructions are only available if specified in the design. While SAMPLE and BYPASS are available during configuration, it is recommended that boundary-scan operations not be performed during this transitory period.

In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA device, and to read back the configuration data.

All of the XC4000 boundary-scan modes are supported in the XC5200 family. Three additional outputs for the User-Register are provided (Reset, Update, and Shift), repre-



Figure 20: Boundary Scan Schematic Example

Even if the boundary scan symbol is used in a schematic, the input pins TMS, TCK, and TDI can still be used as inputs to be routed to internal logic. Care must be taken not to force the chip into an undesired boundary scan state by inadvertently applying boundary scan input patterns to these pins. The simplest way to prevent this is to keep TMS High, and then apply whatever signal is desired to TDI and TCK.

Avoiding Inadvertent Boundary Scan

If TMS or TCK is used as user I/O, care must be taken to ensure that at least one of these pins is held constant during configuration. In some applications, a situation may occur where TMS or TCK is driven during configuration. This may cause the device to go into boundary scan mode and disrupt the configuration process.

To prevent activation of boundary scan during configuration, do either of the following:

- TMS: Tie High to put the Test Access Port controller in a benign RESET state
- TCK: Tie High or Low—do not toggle this clock input.

For more information regarding boundary scan, refer to the Xilinx Application Note XAPP 017, "*Boundary Scan in XC4000 and XC5200 Devices.*"

Power Distribution

Power for the FPGA is distributed through a grid to achieve high noise immunity and isolation between logic and I/O. Inside the FPGA, a dedicated Vcc and Ground ring surrounding the logic array provides power to the I/O drivers, as shown in Figure 21. An independent matrix of Vcc and Ground lines supplies the interior logic of the device.

This power distribution grid provides a stable supply and ground for all internal logic, providing the external package power pins are all connected and appropriately decoupled.

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Typically, a 0.1 μF capacitor connected near the Vcc and Ground pins of the package will provide adequate decoupling.

Output buffers capable of driving/sinking the specified 8 mA loads under specified worst-case conditions may be capable of driving/sinking up to 10 times as much current under best case conditions.

Noise can be reduced by minimizing external load capacitance and reducing simultaneous output transitions in the same direction. It may also be beneficial to locate heavily loaded output buffers near the Ground pads. The I/O Block output buffers have a slew-rate limited mode (default) which should be used where output rise and fall times are not speed-critical.



Figure 21: XC5200-Series Power Distribution

Pin Descriptions

There are three types of pins in the XC5200-Series devices:

- · Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated and pulled high with a 20 k Ω - 100 k Ω pull-up resistor.

After configuration, if an IOB is unused it is configured as an input with a 20 k Ω - 100 k Ω pull-up resistor.

Device pins for XC5200-Series devices are described in Table 9. Pin functions during configuration for each of the seven configuration modes are summarized in "Pin Func-



Master Serial mode generates CCLK and receives the configuration data in serial form from a Xilinx serial-configuration PROM.

CCLK speed is selectable as 1 MHz (default), 6 MHz, or 12 MHz. Configuration always starts at the default slow frequency, then can switch to the higher frequency during the first frame. Frequency tolerance is -50% to +50%.

Peripheral Modes

The two Peripheral modes accept byte-wide data from a bus. A RDY/BUSY status is available as a handshake signal. In Asynchronous Peripheral mode, the internal oscillator generates a CCLK burst signal that serializes the byte-wide data. CCLK can also drive slave devices. In the synchronous mode, an externally supplied clock input to CCLK serializes the data.

Slave Serial Mode

In Slave Serial mode, the FPGA receives serial configuration data on the rising edge of CCLK and, after loading its configuration, passes additional data out, resynchronized on the next falling edge of CCLK.

Multiple slave devices with identical configurations can be wired with parallel DIN inputs. In this way, multiple devices can be configured simultaneously.

Serial Daisy Chain

Multiple devices with different configurations can be connected together in a "daisy chain," and a single combined bitstream used to configure the chain of slave devices.

To configure a daisy chain of devices, wire the CCLK pins of all devices in parallel, as shown in Figure 28 on page 114. Connect the DOUT of each device to the DIN of the next. The lead or master FPGA and following slaves each passes resynchronized configuration data coming from a single source. The header data, including the length count, is passed through and is captured by each FPGA when it recognizes the 0010 preamble. Following the length-count data, each FPGA outputs a High on DOUT until it has received its required number of data frames.

After an FPGA has received its configuration data, it passes on any additional frame start bits and configuration data on DOUT. When the total number of configuration clocks applied after memory initialization equals the value of the 24-bit length count, the FPGAs begin the start-up sequence and become operational together. FPGA I/O are normally released two CCLK cycles after the last configuration bit is received. Figure 25 on page 109 shows the start-up timing for an XC5200-Series device.

The daisy-chained bitstream is not simply a concatenation of the individual bitstreams. The PROM file formatter must be used to combine the bitstreams for a daisy-chained configuration.

Multi-Family Daisy Chain

All Xilinx FPGAs of the XC2000, XC3000, XC4000, and XC5200 Series use a compatible bitstream format and can, therefore, be connected in a daisy chain in an arbitrary sequence. There is, however, one limitation. If the chain contains XC5200-Series devices, the master normally cannot be an XC2000 or XC3000 device.

The reason for this rule is shown in Figure 25 on page 109. Since all devices in the chain store the same length count value and generate or receive one common sequence of CCLK pulses, they all recognize length-count match on the same CCLK edge, as indicated on the left edge of Figure 25. The master device then generates additional CCLK pulses until it reaches its finish point F. The different families generate or require different numbers of additional CCLK pulses until they reach F. Not reaching F means that the device does not really finish its configuration, although DONE may have gone High, the outputs became active, and the internal reset was released. For the XC5200-Series device, not reaching F means that readback cannot be initiated and most boundary scan instructions cannot be used.

The user has some control over the relative timing of these events and can, therefore, make sure that they occur at the proper time and the finish point F is reached. Timing is controlled using options in the bitstream generation software.

XC5200 devices always have the same number of CCLKs in the power up delay, independent of the configuration mode, unlike the XC3000/XC4000 Series devices. To guarantee all devices in a daisy chain have finished the power-up delay, tie the INIT pins together, as shown in Figure 27.

XC3000 Master with an XC5200-Series Slave

Some designers want to use an XC3000 lead device in peripheral mode and have the I/O pins of the XC5200-Series devices all available for user I/O. Figure 22 provides a solution for that case.

This solution requires one CLB, one IOB and pin, and an internal oscillator with a frequency of up to 5 MHz as a clock source. The XC3000 master device must be configured with late Internal Reset, which is the default option.

One CLB and one IOB in the lead XC3000-family device are used to generate the additional CCLK pulse required by the XC5200-Series devices. When the lead device removes the internal RESET signal, the 2-bit shift register responds to its clock input and generates an active Low output signal for the duration of the subsequent clock period. An external connection between this output and CCLK thus creates the extra CCLK pulse.



Figure 23: Circuit for Generating CRC-16

Configuration Sequence

There are four major steps in the XC5200-Series power-up configuration sequence.

- Power-On Time-Out
- Initialization
- Configuration
- Start-Up

The full process is illustrated in Figure 24.

Power-On Time-Out

An internal power-on reset circuit is triggered when power is applied. When V_{CC} reaches the voltage at which portions of the FPGA begin to operate (i.e., performs a write-and-read test of a sample pair of configuration memory bits), the programmable I/O buffers are 3-stated with active high-impedance pull-up resistors. A time-out delay — nominally 4 ms — is initiated to allow the power-supply voltage to stabilize. For correct operation the power supply must reach V_{CC} (min) by the end of the time-out, and must not dip below it thereafter.

There is no distinction between master and slave modes with regard to the time-out delay. Instead, the INIT line is used to ensure that all daisy-chained devices have completed initialization. Since XC2000 devices do not have this signal, extra care must be taken to guarantee proper operation when daisy-chaining them with XC5200 devices. For proper operation with XC3000 devices, the RESET signal, which is used in XC3000 to delay configuration, should be connected to INIT.

If the time-out delay is insufficient, configuration should be delayed by holding the $\overline{\text{INIT}}$ pin Low until the power supply has reached operating levels.

This delay is applied only on power-up. It is <u>not applied</u> when reconfiguring an FPGA by pulsing the <u>PROGRAM</u> pin Low. During all three phases — Power-on, Initialization, and Configuration — DONE is held Low; HDC, LDC, and INIT are active; DOUT is driven; and all I/O buffers are disabled.

Initialization

This phase clears the configuration memory and establishes the configuration mode.

The configuration memory is cleared at the rate of one frame per internal clock cycle (nominally 1 MHz). An open-drain bidirectional signal, INIT, is released when the configuration memory is completely cleared. The device then tests for the absence of an external active-low level on INIT. The mode lines are sampled two internal clock cycles later (nominally 2 μ s).

The master device waits an additional 32 μ s to 256 μ s (nominally 64-128 μ s) to provide adequate time for all of the slave devices to recognize the release of INIT as well. Then the master device enters the Configuration phase.



Figure 24: Configuration Sequence

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	Description	S	Symbol	Min	Max	Units
	INIT (High) setup time	1	T _{IC}	5		μs
	D0 - D7 setup time	2	T _{DC}	60		ns
	D0 - D7 hold time	3	T _{CD}	0		ns
COLK	CCLK High time		T _{CCH}	50		ns
	CCLK Low time		T _{CCL}	60		ns
	CCLK Frequency		F _{CC}		8	MHz

Notes: 1. Peripheral Synchronous mode can be considered Slave Parallel mode. An external CCLK provides timing, clocking in the first data byte on the second rising edge of CCLK after INIT goes high. Subsequent data bytes are clocked in on every eighth consecutive rising edge of CCLK.

2. The RDY/BUSY line goes High for one CCLK period after data has been clocked in, although synchronous operation does not require such a response.

3. The pin name RDY/BUSY is a misnomer. In synchronous peripheral mode this is really an ACKNOWLEDGE signal. 4.Note that data starts to shift out serially on the DOUT pin 0.5 CCLK periods after it was loaded in parallel. Therefore, additional CCLK pulses are clearly required after the last byte has been loaded.

Figure 34: Synchronous Peripheral Mode Programming Switching Characteristics



Pin Functions During Configuration Table 13.

CONFIGURATION MODE: <m2:m1:m0></m2:m1:m0>							
SLAVE <1:1:1>	MASTER-SER <0:0:0>	SYN.PERIPH <0:1:1>	ASYN.PERIPH <1:0:1>	MASTER-HIGH <1:1:0>	MASTER-LOW <1:0:0>	EXPRESS <0:1:0>	OPERATION
	1		•	A16	A16		GCK1-I/O
				A17	A17		I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
			·				I/O
M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	M1 (LOW) (I)	M1 (HIGH) (I)	I/O
M0 (HIGH) (I)	M0 (LOW) (I)	M0 (HIGH) (I)	M0 (HIGH) (I)	M0 (LOW) (I)	M0 (LOW) (I)	M0 (LOW) (I)	I/O
M2 (HIGH) (I)	M2 (LOW) (I)	M2 (LOW) (I)	M2 (HIGH) (I)	M2 (HIGH) (I)	M2 (HIGH) (I)	M2 (LOW) (I)	I/O
							GCK2-I/O
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	INIT-ERROR	I/O
							I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
			•	1	T	T	GCK3-I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
			CSO (I)				1/0
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
			RS (I)		//		1/0
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	1/0
				DATA 1 (I)	DATA 1 (I)	DATA1(I)	1/0
		RDY/BUSY	RDY/BUSY	RCLK	RCLK		1/0
DIN (I)	DIN (I)						1/0
							1/0
	CCLK (U)		CCLK (U)	CCLK (U)	CCLK (O)		
TDO	TDO	IDO		100	1DO	100	100-1/0
			VVS (I)	AU	AU		
			CS1 (I)	A1	A1	CS1 (I)	GCK4-I/O
			031(1)	A2 A2	A2		1/0
				A3	AJ		1/0
				Δ5	Δ5		1/0
				A6	A6		1/0
				Δ7	Δ7		1/0
				Δ <u>Α</u>	<u>A8</u>		1/0
				Α9	A9		1/O
				A10	A10		1/O
				A11	A11		/O
				A12	A12		
				A13	A13		I/O
				A14	A14		/O
				A15	A15		I/O
							ALL OTHERS

Notes: 1. A shaded table cell represents a 20-kΩ to 100-kΩ pull-up resistor before and during configuration.
2. (I) represents an input (O) represents an output.
3. INIT is an open-drain output during configuration.



XC5200 Switching Characteristics

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or device families. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.¹

XC5200 Operating Conditions

Symbol	Description	Min	Max	Units
V _{cc}	Supply voltage relative to GND Commercial: 0°C to 85°C junction	4.75	5.25	V
	Supply voltage relative to GND Industrial: -40°C to 100°C junction	4.5	5.5	V
V _{IHT}	High-level input voltage — TTL configuration	2.0	V _{cc}	V
V _{ILT}	Low-level input voltage — TTL configuration	0	0.8	V
V _{IHC}	High-level input voltage — CMOS configuration	70%	100%	V _{cc}
V _{ILC}	Low-level input voltage — CMOS configuration	0	20%	V _{cc}
T _{IN}	Input signal transition time		250	ns

XC5200 DC Characteristics Over Operating Conditions

Symbol	Description	Min	Max	Units
V _{OH}	High-level output voltage @ I _{OH} = -8.0 mA, V _{CC} min	3.86		V
V _{OL}	Low-level output voltage @ I _{OL} = 8.0 mA, V _{CC} max		0.4	V
I _{cco}	Quiescent FPGA supply current (Note 1)		15	mA
I _{IL}	Leakage current	-10	+10	μΑ
C _{IN}	Input capacitance (sample tested)		15	pF
I _{RIN}	Pad pull-up (when selected) @ $V_{IN} = 0V$ (sample tested)	0.02	0.30	mA
Mate: 4	With an evidence transferred all applicant at Visc as CNID, either TTL as CMOC is not a		a a safi as sua al	

Note: 1. With no output current loads, all package pins at Vcc or GND, either TTL or CMOS inputs, and the FPGA configured with a tie option.

XC5200 Absolute Maximum Ratings

Symbol	Description		Units
V _{cc}	Supply voltage relative to GND	-0.5 to +7.0	V
V _{IN}	Input voltage with respect to GND	-0.5 to V _{CC} +0.5	V
V _{TS}	Voltage applied to 3-state output	-0.5 to V _{CC} +0.5	V
T _{STG}	Storage temperature (ambient)	-65 to +150	°C
T _{SOL}	Maximum soldering temperature (10 s @ 1/16 in. = 1.5 mm)	+260	°C
TJ	Junction temperature in plastic packages	+125	°C
	Junction temperature in ceramic packages	+150	°C

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

1. Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

XC5200 Guaranteed Input and Output Parameters (Pin-to-Pin)

All values listed below are tested directly, and guaranteed over the operating conditions. The same parameters can also be derived indirectly from the Global Buffer specifications. The delay calculator uses this indirect method, and may overestimate because of worst-case assumptions. When there is a discrepancy between these two methods, the values listed below should be used, and the derived values should be considered conservative overestimates.

	-6	-5	-4	-3		
Description	Symbol	Device	Max (ns)	Max (ns)	Max (ns)	Max (ns)
Global Clock to Output Pad (fast)	T _{ICKOF}	XC5202	16.9	15.1	10.9	9.8
CLB Direct IOB		XC5204	17.1	15.3	11.3	9.9
	(Max)	XC5206	17.2	15.4	11.9	10.8
□ □ FÁST :		XC5210	17.2	15.4	12.8	11.2
Global Clock-to-Output Deray		XC5215	19.0	17.0	12.8	11.7
Global Clock to Output Pad (slew-limited)	Т _{IСКО}	XC5202	21.4	18.7	12.6	11.5
CLB Direct IOB		XC5204	21.6	18.9	13.3	11.9
BUFG Q Connect	(Max)	XC5206	21.7	19.0	13.6	12.5
		XC5210	21.7	19.0	15.0	12.9
Global Clock-to-Output Delay		XC5215	24.3	21.2	15.0	13.1
Input Set-up Time (no delay) to CLB Flip-Flop	T _{PSUF}	XC5202	2.5	2.0	1.9	1.9
IOB(NODELAY) Direct CLB		XC5204	2.3	1.9	1.9	1.9
	(Min)	XC5206	2.2	1.9	1.9	1.9
		XC5210	2.2	1.9	1.9	1.8
BUFG		XC5215	2.0	1.8	1.7	1.7
Input Hold Time (no delay) to CLB Flip-Flop	T _{PHF}	XC5202	3.8	3.8	3.5	3.5
IOB(NODELAY) Direct CLB		XC5204	3.9	3.9	3.8	3.6
Set-up	(Min)	XC5206	4.4	4.4	4.4	4.3
		XC5210	5.1	5.1	4.9	4.8
BUFG		XC5215	5.8	5.8	5.7	5.6
Input Set-up Time (with delay) to CLB Flip-Flop DI Input	T _{PSU}	XC5202	7.3	6.6	6.6	6.6
		XC5204	7.3	6.6	6.6	6.6
		XC5206	7.2	6.5	6.4	6.3
		XC5210	7.2	6.5	6.0	6.0
BUFG		XC5215	6.8	5.7	5.7	5.7
Input Set-up Time (with delay) to CLB Flip-Flop F Input	T _{PSUL}	XC5202	8.8	7.7	7.5	7.5
IOB Direct CLB		XC5204	8.6	7.5	7.5	7.5
	(Min)	XC5206	8.5	7.4	7.4	7.4
		XC5210	8.5	7.4	7.4	7.3
BUFG		XC5215	8.5	7.4	7.4	7.2
Input Hold Time (with delay) to CLB Flip-Flop IOB Direct CLB Input Set-up & Hold Time BUEG	Т _{РН} (Min)	XC52xx	0	0	0	0
BOFG	1		1	1	1	

Note: 1. These measurements assume that the CLB flip-flop uses a direct interconnect to or from the IOB. The INREG/ OUTREG properties, or XACT-Performance, can be used to assure that direct connects are used. t_{PSU} applies only to the CLB input DI that bypasses the look-up table, which only offers direct connects to IOBs on the left and right edges of the die. t_{PSUL} applies to the CLB inputs F that feed the look-up table, which offers direct connect to IOBs on all four edges, as do the CLB Q outputs.

2. When testing outputs (fast or slew-limited), half of the outputs on one side of the device are switching.



Pin	Description	PC84	PQ100	VQ100	TQ144	PG156	PQ160	Boundary Scan Order
57.	I/O	-	-	-	47	E16	53	306
58.	I/O	38	34	31	48	F16	54	312
59.	I/O	39	35	32	49	G14	55	315
60.	I/O	-	36	33	50	G15	56	318
61.	I/O	-	37	34	51	G16	57	324
62.	I/O	40	38	35	52	H16	58	327
63.	I/O (ERR, INIT)	41	39	36	53	H15	59	330
	VCC	42	40	37	54	H14	60	-
	GND	43	41	38	55	J14	61	-
64.	I/O	44	42	39	56	J15	62	336
65.	I/O	45	43	40	57	J16	63	339
66.	I/O	-	44	41	58	K16	64	348
67.	I/O	-	45	42	59	K15	65	351
68.	I/O	46	46	43	60	K14	66	354
69.	I/O	47	47	44	61	L16	67	360
70.	I/O	-	-	-	62	M16	68	363
71.	I/O	-	-	-	63	L15	69	366
	GND	-	-	-	64	L14	70	-
72.	I/O	-	-	-	-	N16	71	372
73.	I/O	-	-	-	-	M15	72	375
74.	I/O	48	48	45	65	P16	73	378
75.	I/O	49	49	46	66	M14	74	384
76.	I/O	-	-	-	67	N15	75	387
77.	I/O	-	-	-	68	P15	76	390
78.	I/O	50	50	47	69	N14	77	396
79.	I/O	51	51	48	70	R16	78	399
	GND	52	52	49	71	P14	79	-
	DONE	53	53	50	72	R15	80	-
	VCC	54	54	51	73	P13	81	-
	PROG	55	55	52	74	R14	82	-
80.	I/O (D7)	56	56	53	75	T16	83	408
81.	GCK3 (I/O)	57	57	54	76	T15	84	411
82.	I/O	-	-	-	77	R13	85	420
83.	I/O	-	-	-	78	P12	86	423
84.	I/O (D6)	58	58	55	79	T14	87	426
85.	I/O	-	59	56	80	T13	88	432
	GND	-	-	-	81	P11	91	-
86.	I/O	-	-	-	82	R11	92	435
87.	1/0	-	-	-	83	T11	93	438
88.	I/O (D5)	59	60	57	84	T10	94	444
89	$I/O(\overline{CSO})$	60	61	58	85	P10	95	447
90	1/0	-	62	59	86	R10	96	450
91	1/O	-	63	60	87	T9	97	456
92	I/O (D4)	61	64	61	88	R9	98	459
93		62	65	62	89	PQ	99	462
	VCC	63	66	63	90	R8	100	-
	GND	64	67	64	91	P8	101	-
94	I/O (D3)	65	68	65	92	TR	102	468
95	I/O(RS)	66	69	66	93	.0 T7	103	471
96	1/0	-	70	67	94	Те	104	Δ7Λ
97	1/0	_	-	-	95	R7	10-	480
98	",C I/O (D2)	67	71	68	90	P7	105	483
55.	" (() _)	51					100	-00

57	VII	INIX®
≺⊾		

Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
42.	I/O	-	-	-	-	-	28	C11	32	273
43.	I/O	25	19	16	23	25	29	B11	33	279
44.	I/O	26	20	17	24	26	30	A12	34	282
45.	I/O	-	-	-	25	27	31	B12	35	285
46.	I/O	-	-	-	26	28	32	A13	36	291
	GND	-	-	-	27	29	33	C12	37	-
47.	I/O	-	-	-	-	30	34	A15	40	294
48.	I/O	-	-	-	-	31	35	C13	41	297
49.	I/O	27	21	18	28	32	36	B14	42	303
50.	I/O	-	22	19	29	33	37	A16	43	306
51.	I/O	-	-	-	30	34	38	B15	44	309
52.	I/O	-	-	-	31	35	39	C14	45	315
53.	I/O	28	23	20	32	36	40	A17	46	318
54.	I/O	29	24	21	33	37	41	B16	47	321
55.	M1 (I/O)	30	25	22	34	38	42	C15	48	330
	GND	31	26	23	35	39	43	D15	49	-
56.	M0 (I/O)	32	27	24	36	40	44	A18	50	333
	VCC	33	28	25	37	41	45	D16	55	-
57.	M2 (I/O)	34	29	26	38	42	46	C16	56	336
58.	GCK2 (I/O)	35	30	27	39	43	47	B17	57	339
59.	I/O (HDC)	36	31	28	40	44	48	E16	58	348
60.	I/O	-	-	-	41	45	49	C17	59	351
61.	I/O	-	-	-	42	46	50	D17	60	354
62.	I/O	-	32	29	43	47	51	B18	61	360
63.	I/O (LDC)	37	33	30	44	48	52	E17	62	363
64.	I/O	-	-	-	-	49	53	F16	63	372
65.	I/O	-	-	-	-	50	54	C18	64	375
	GND	-	-	-	45	51	55	G16	67	-
66.	I/O	-	-	-	46	52	56	E18	68	378
67.	I/O	-	-	-	47	53	57	F18	69	384
68.	I/O	38	34	31	48	54	58	G17	70	387
69.	I/O	39	35	32	49	55	59	G18	71	390
70.	I/O	-	-	-	-	-	60	H16	72	396
71.	I/O	-	-	-	-	-	61	H17	73	399
72.	I/O	-	36	33	50	56	62	H18	74	402
73.	I/O	-	37	34	51	57	63	J18	75	408
74.	I/O	40	38	35	52	58	64	J17	76	411
75.	I/O (ERR, INIT)	41	39	36	53	59	65	J16	77	414
	VCC	42	40	37	54	60	66	J15	78	-
	GND	43	41	38	55	61	67	K15	79	-
76.	I/O	44	42	39	56	62	68	K16	80	420
77.	I/O	45	43	40	57	63	69	K17	81	423
78.	I/O	-	44	41	58	64	70	K18	82	426
79.	I/O	-	45	42	59	65	71	L18	83	432
80.	I/O	-	-	-	-	-	72	L17	84	435
81.	I/O	-	-	-	-	-	73	L16	85	438
82.	I/O	46	46	43	60	66	74	M18	86	444
83.	I/O	47	47	44	61	67	75	M17	87	447
84.	I/O	-	-	-	62	68	76	N18	88	450
85.	I/O	-	-	-	63	69	77	P18	89	456
	GND	-	-	-	64	70	78	M16	90	-
86.	I/O	-	-	-	-	71	79	T18	93	459



Pin	Description	PC84	PQ100	VQ100	TQ144	PQ160	TQ176	PG191	PQ208	Boundary Scan Order
87.	I/O	-	-	-	-	72	80	P17	94	468
88.	I/O	48	48	45	65	73	81	N16	95	471
89.	I/O	49	49	46	66	74	82	T17	96	480
90.	I/O	-	-	-	67	75	83	R17	97	483
91.	I/O	-	-	-	68	76	84	P16	98	486
92.	I/O	50	50	47	69	77	85	U18	99	492
93.	I/O	51	51	48	70	78	86	T16	100	495
	GND	52	52	49	71	79	87	R16	101	-
	DONE	53	53	50	72	80	88	U17	103	-
	VCC	54	54	51	73	81	89	R15	106	-
	PROG	55	55	52	74	82	90	V18	108	-
94.	I/O (D7)	56	56	53	75	83	91	T15	109	504
95.	GCK3 (I/O)	57	57	54	76	84	92	U16	110	507
96.	I/O	-	-	-	77	85	93	T14	111	516
97.	I/O	-	-	-	78	86	94	U15	112	519
98.	I/O (D6)	58	58	55	79	87	95	V17	113	522
99.	I/O	-	59	56	80	88	96	V16	114	528
100.	I/O	-	-	-	-	89	97	T13	115	531
101.	I/O	-	-	-	-	90	98	U14	116	534
	GND	-	-	-	81	91	99	T12	119	-
102.	I/O	-	-	-	82	92	100	U13	120	540
103.	I/O	-	-	-	83	93	101	V13	121	543
104.	I/O (D5)	59	60	57	84	94	102	U12	122	552
105	$I/O(\overline{CS0})$	60	61	58	85	95	103	V12	123	555
106	1/O	-	-	-	-	-	104	T11	124	558
107	1/O	-	-	-	-	-	105	U11	125	564
108.	1/O	-	62	59	86	96	106	V11	126	567
109.	1/O	-	63	60	87	97	107	V10	127	570
110.	I/O (D4)	61	64	61	88	98	108	U10	128	576
111.	1/O	62	65	62	89	99	109	T10	129	579
	VCC	63	66	63	90	100	110	R10	130	-
	GND	64	67	64	91	100	111	R9	131	
112		65	68	65	92	102	112	Т9	132	588
113.	$I/O(\overline{RS})$	66	69	66	93	103	113	10	133	591
114	1/0	-	70	67	94	104	114	V9	134	600
115	1/0	_	-	-	95	105	115	V8	135	603
116	1/O		_	_	-	-	116	118	136	612
117	1/O		_	_	_	_	117	тя	137	615
118	I/O (D2)	67	71	68	96	106	118	10	138	618
110.	1/0 (02)	68	72	69	90	100	110	117	130	624
120	1/0	-	12	03	08	107	120	Ve	139	627
120.	1/0		_		90	100	120	116	140	630
121.	GND		_		100	110	121	T7	141	-
100		-	-	-	100	111	122	115	142	626
122.	1/0	-	-	-	-	112	123	03 Te	145	630
123.		-	- 70	-	-	112	124	10	140	642
124.	1/O (DT)	70	73	70	101	113	120	V3	147	642
125.	(RCLK-BUSY/RD Y)	70	74	71	102	114	120	V2	140	040
126.	I/O	-	-	-	103	115	127	U4	149	651
127.	I/O	-	-	-	104	116	128	T5	150	654
128.	I/O (D0, DIN)	71	75	72	105	117	129	U3	151	660
129.	I/O (DOUT)	72	76	73	106	118	130	T4	152	663
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Pin	Description	PC84	TQ144	PQ160	TQ176	PQ208	PG223	BG225	PQ240	Boundary Scan Order
7.	I/O (A10)	5	133	147	162	190	G1	A6	220	135
8.	I/O (A11)	6	134	148	163	191	G2	B6	221	138
	VCC	-	-	-	-	-	-	VCC*	222	-
9.	I/O	-	-	-	-	-	H4	C6	223	141
10.	I/O	-	-	-	-	-	G4	F7	224	150
11.	I/O	-	135	149	164	192	F1	A5	225	153
12.	I/O	-	136	150	165	193	E1	B5	226	162
	GND	-	137	151	166	194	G3	GND*	227	-
13.	I/O	-	-	-	-	195	F2	D6	228	165
14.	I/O	-	-	-	167	196	D1	C5	229	171
15.	I/O	-	-	152	168	197	C1	A4	230	174
16.	I/O	-	-	153	169	198	E2	E6	231	177
17.	I/O (A12)	7	138	154	170	199	F3	B4	232	183
18.	I/O (A13)	8	139	155	171	200	D2	D5	233	186
19.	I/O	-	-	-	-	-	F4	A3	234	189
20.	I/O	-	-	-	-	-	E4	C4	235	195
21.	I/O	-	140	156	172	201	B1	B3	236	198
22.	I/O	-	141	157	173	202	E3	F6	237	201
23.	I/O (A14)	9	142	158	174	203	C2	A2	238	210
24.	I/O (A15)	10	143	159	175	204	B2	C3	239	213
	VCC	11	144	160	176	205	D3	VCC*	240	-
	GND	12	1	1	1	2	D4	GND*	1	-
25.	GCK1 (A16, I/O)	13	2	2	2	4	C3	D4	2	222
26.	I/O (A17)	14	3	3	3	5	C4	B1	3	225
27.	I/O	-	4	4	4	6	B3	C2	4	231
28.	I/O	-	5	5	5	7	C5	E5	5	234
29.	I/O (TDI)	15	6	6	6	8	A2	D3	6	237
30.	I/O (TCK)	16	7	7	7	9	B4	C1	7	243
31.	I/O	-	-	8	8	10	C6	D2	8	246
32.	I/O	-	-	9	9	11	A3	G6	9	249
33.	I/O	-	-	-	-	12	B5	E4	10	255
34.	I/O	-	-	-	-	13	B6	D1	11	258
35.	I/O	-	-	-	-	-	D5	E3	12	261
36.	I/O	-	-	-	-	-	D6	E2	13	267
	GND	-	8	10	10	14	C7	GND*	14	-
37.	I/O	-	9	11	11	15	A4	F5	15	270
38.	I/O	-	10	12	12	16	A5	E1	16	273
39.	I/O (TMS)	17	11	13	13	17	B7	F4	17	279
40.	I/O	18	12	14	14	18	A6	F3	18	282
	VCC	-	-	-	-	-	-	VCC*	19	-
41.	I/O	-	-	-	-	-	D7	F2	20	285
42.	I/O	-	-	-	-	-	D8	F1	21	291
43.	I/O	-	-	-	15	19	C8	G4	23	294
44.	I/O	-	-	-	16	20	A7	G3	24	297
45.	I/O	-	13	15	17	21	B8	G2	25	306
46.	I/O	-	14	16	18	22	A8	G1	26	309
47.	I/O	19	15	17	19	23	B9	G5	27	318
48.	I/O	20	16	18	20	24	C9	H3	28	321
	GND	21	17	19	21	25	D9	GND*	29	-
	VCC	22	18	20	22	26	D10	VCC*	30	-
49.	I/O	23	19	21	23	27	C10	H4	31	327



Pin	Description	PQ160	HQ208	HQ240	PG299	BG225	BG352	Boundary Scan Order
146.	I/O	-	-	-	R17	-	AD6	750
147.	I/O	-	-	-	T18	-	AC7	756
148.	I/O	73	95	113	U19	R13	AF4	759
149.	I/O	74	96	114	V19	N12	AF3	768
150.	I/O	75	97	115	R16	P13	AD5	771
151.	I/O	76	98	116	T17	K10	AE3	774
152.	I/O	77	99	117	U18	R14	AD4	780
153.	I/O	78	100	118	X20	N13	AC5	783
	GND	79	101	119	W20	GND*	GND*	_
	DONE	80	103	120	V18	P14	AD3	_
	VCC	81	106	121	X19	VCC*	VCC*	_
	PROG	82	108	122	U17	M12	AC4	-
154.	I/O (D7)	83	109	123	W19	P15	AD2	792
155	GCK3 (I/O)	84	110	124	W18	N14	AC3	795
156		85	111	125	T15	111	ΔB4	804
150.	1/0	86	112	120	110	M13		807
157.	1/0		-	120	V17	N15		810
150.	1/0		_	127	V17 V19	M14	AA3	816
159.	1/0	-	-	120	1115	10114	AR3 AR2	810
100.	1/0	-	-	-	U13 T14	-	ADZ	019
101.		- 07	-	-	114	-	ACT	020
162.	I/O (D6)	87	113	129	VV17	J10	¥3	831
163.	1/0	88	114	130	V16	LIZ	AAZ	834
164.	1/0	89	115	131	X17	M15	AA1	840
165.	1/0	90	116	132	U14	L13	VV4	843
166.	1/0	-	11/	133	V15	L14	W3	846
167.	1/0	-	118	134	113	K11	Y2	852
168.	1/0	-	-	-	W16	-	Y1	855
169.	1/0	-	-	-	W15	-	V4	858
	GND	91	119	135	X16	GND*	GND*	-
170.	1/0	-	-	136	U13	L15	V3	864
171.	1/0	-	-	137	V14	K12	W2	867
172.	1/0	92	120	138	W14	K13	04	870
173.	1/0	93	121	139	V13	K14	U3	876
	VCC	-	-	140	X15	VCC*	VCC*	-
174.	I/O (D5)	94	122	141	T12	K15	V2	879
175.	I/O (CS0)	95	123	142	X14	J12	V1	882
176.	1/0	-	-	-	X13	-	T1	888
177.	1/0	-	-	-	V12	-	R4	891
178.	I/O	-	124	144	W12	J13	R3	894
179.	I/O	-	125	145	T11	J14	R2	900
180.	I/O	96	126	146	X12	J15	R1	903
181.	I/O	97	127	147	U11	J11	P3	906
182.	I/O (D4)	98	128	148	V11	H13	P2	912
183.	I/O	99	129	149	W11	H14	P1	915
	VCC	100	130	150	X10	VCC*	VCC*	-
	GND	101	131	151	X11	GND*	GND*	-
184.	I/O (D3)	102	132	152	W10	H12	N2	924
185.	I/O (RS)	103	133	153	V10	H11	N4	927
186.	I/O	104	134	154	T10	G14	N3	936
187.	I/O	105	135	155	U10	G15	M1	939
188.	I/O	-	136	156	X9	G13	M2	942
189.	I/O	-	137	157	W9	G12	M3	948

XC5200 Series Field Programmable Gate Arrays

∑XILINX[®]

Product Availability

	PINS	64	84	100	100	144	156	160	176	191	208	208	223	225	240	240	299	352
TYPE		Plast. VQFP	Plast. PLCC	Plast. PQFP	Plast. VQFP	Plast. TQFP	Ceram. PGA	Plast. PQFP	Plast. TQFP	Ceram. PGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA
CODE		VQ64*	PC84	PQ100	VQ100	TQ144	PG156	PQ160	т0176	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	BG352
	-6	CI	CI	CI	CI	CI	CI											
XC5202	-5	CI	CI	CI	CI	CI	CI											
700202	-4	С	С	С	С	С	С											
	-3	С	С	С	С	С	С											
XC5204	-6		CI	CI	CI	CI	CI	CI										
	-5		CI	CI	CI	CI	CI	CI										
700204	-4		С	С	С	С	С	С										
	-3		С	С	С	С	С	С										
	-6		CI	CI	CI	CI		CI	CI	CI		CI						
XC5206	-5		CI	CI	CI	CI		CI	CI	CI		CI						
700200	-4		С	С	С	С		С	С	С		С						
	-3		С	С	С	С		С	С	С		С						
	-6		CI			CI		CI	CI			CI	CI	CI		CI		
XC5210	-5		CI			CI		CI	CI			CI	CI	CI		CI		
	-4		С			С		С	С			С	С	С		С		
	-3		С			С		С	С			С	С	С		С		
	-6							CI			CI			CI	CI		CI	CI
XC5215	-5							С			С			С	С		С	С
7.00210	-4							С			С			С	С		С	С
	-3							С			С			С	С		С	С

C = Commercial $T_J = 0^{\circ}$ to +85°C

I= Industrial $T_J = -40^{\circ}C$ to $+100^{\circ}C$

* VQ64 package supports Master Serial, Slave Serial, and Express configuration modes only.

User I/O Per Package

_	Мах	Package Type																
Device	I/O	VQ64	PC84	PQ100	VQ100	TQ144	PG156	PQ160	TQ176	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	BG352
XC5202	84	52	65	81	81	84	84											
XC5204	124		65	81	81	117	124	124										
XC5206	148		65	81	81	117		133	148	148		148						
XC5210	196		65			117		133	149			164	196	196		196		
XC5215	244							133			164			196	197		244	244

7/8/98

Ordering Information





Revisions

Version	Description
12/97	Rev 5.0 added -3, -4 specification
7/98	Rev 5.1 added Spartan family to comparison, removed HQ304
11/98	Rev 5.2 All specifications made final.